

H2M120Q040

Silicon Carbide MOSFET
N-CHANNEL ENHANCEMENT MODE

Features

- Low On-Resistance and High Current Density
- Low Capacitance for High Frequency Operation
- Ultra-high Avalanche Ruggedness
- Positive Temperature Coefficient Device
- Low impedance Kelvin source pin-out
- RoHS Compliant and Halogen Free

Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Capable of 175°C High T_j Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems

Applications

- Switching Mode Power Supply
- DC/DC Converters, UPS, and PFC
- EV Charging Station
- Motor Drives
- Power Inverters
- Solar/Wind Renewable Energy

Absolute Maximum Ratings ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	$V_{DS,max}$	$V_{GS}=0V, I_{DS}=100\mu A$	1200	V
Continuous Drain Current	I_D	$V_{GS}=20V, T_c=25^\circ\text{C}$	65	A
		$V_{GS}=20V, T_c=100^\circ\text{C}$	48	
Pulse Drain Current	$I_{D,pulse}$	t_{PW} limitation per Fig.15	237	
Power Dissipation	P_D	$T_c=25^\circ\text{C}$	341	W
Recommend Gate Source Voltage	$V_{GS,op}$	Static, recommended DC operating values	-5 to 20	V
Maximum Gate Source Voltage	$V_{GS,max}$	Transient operating limit (AC $f > 1\text{Hz}$, duty cycle $< 1\%$)	-10 to 25	
Junction & Storage Temperature	T_j, T_{stg}		-55 to 175	$^\circ\text{C}$
Soldering Temperature	T_L		260	
Mounting Torque	M_D	M3 or 6-32 screw	1.0	Nm

Thermal Resistance

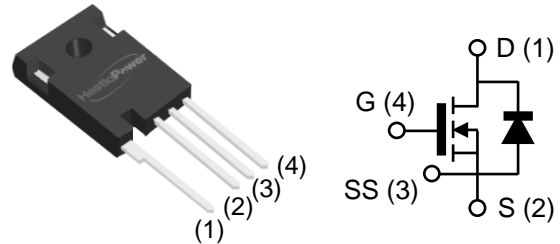
Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction to Case	$R_{\theta,jc}$		0.44		$^\circ\text{C/W}$

Product Summary

V_{DS}	1200V
$I_D(@25^\circ\text{C})$	65A
$R_{DS(on)}$	40mΩ



Circuit Diagram



Part Number	Package	Marking
H2M120Q040	TO-247-4L	H2M120Q040

Description

The H2M120Q040 1200V, 40mΩ silicon carbide power MOSFET is an N-channel enhancement mode device. Exploiting the outstanding wide bandgap material properties, this device shows high current density and great switching behavior. Thanks for the excellent thermal conductivity and many advantages of SiC, this device significantly improved in thermal capability and temperature independent switching behavior.

Electrical Characteristics (T_c = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} =0V, I _{DS} =100μA	1200			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =10V, I _{DS} =40mA	1.5	2.9	4.5	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =1200V, V _{GS} =0V		<1	50	μA
		V _{DS} =1200V, V _{GS} =0V T _j =175°C		10		
Gate-Source Leakage Current	I _{GSS}	V _{GS} =20V, V _{DS} =0V			250	nA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} =20V, I _{DS} =30A		40	50	mΩ
		V _{GS} =20V, I _{DS} =30A, T _j =175°C		69		
Transconductance	g _{fs}	V _{DS} =9.7V, I _{DS} =30A		13		S
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =800V f=1MHz, V _{AC} =25mV		5757		pF
Output Capacitance	C _{oss}			156		
Reverse Transfer Capacitance	C _{rss}			9		
Effective Output Capacitance, Energy Related	C _{o(er)}	V _{GS} =0V, V _{DS} =0 to 800V		202		pF
Effective Output Capacitance, Time Related	C _{o(tr)}	I _D =const., V _{GS} =0V, V _{DS} =0 to 800V		284		
Turn On Delay Time	t _{d(on)}	V _{DS} =800V, V _{GS} =-5/+20V, I _D =30A, R _L =27Ω, R _{G(ext)} = 2.7 Ω		35.2		ns
Rise Time	t _r			56		
Turn Off Delay Time	t _{d(off)}			48		
Fall Time	t _f			44.8		
C _{oss} Stored Energy	E _{oss}	V _{GS} =0V, V _{DS} =800V f=1MHz, V _{AC} =25mV		63		μJ
Turn-on Switching Energy	E _{on}	V _{DS} =800V, V _{GS} =0/+20V, I _D =30A,		224		
Turn-off Switching Energy	E _{off}	R _{G(ext)} = 2.7 Ω		57.4		
Internal Gate Resistance	R _{G(int.)}	f=1MHz, V _{AC} =25mV		0.5		Ω

Built-in SiC Diode Characteristics (T_c = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Typ.	Unit
Inverse Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _{SD} =7.5A	2.5	V
Continuous Diode Forward Current	I _S	V _{GS} =0V, T _c =25°C	83	A
Reverse Recovery Time	t _{rr}	V _{GS} =0V,	61	ns
Reverse Recovery Charge	Q _{rr}	I _{SD} =30A, V _{DS} =400V,	155	nC
Peak Reverse Recovery Current	I _{rrm}	di/dt=300A/μs	4.8	A

Gate Charge Characteristics (T_c = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Gate to Source Charge	Q _{GS}	V _{DS} =800V, V _{GS} =-5/+20V, I _D =30A	98	nC
Gate to Drain Charge	Q _{GD}		84	
Total Gate Charge	Q _G		298	
Gate plateau voltage	V _{pl}		8.9	V

Typical Device Performance

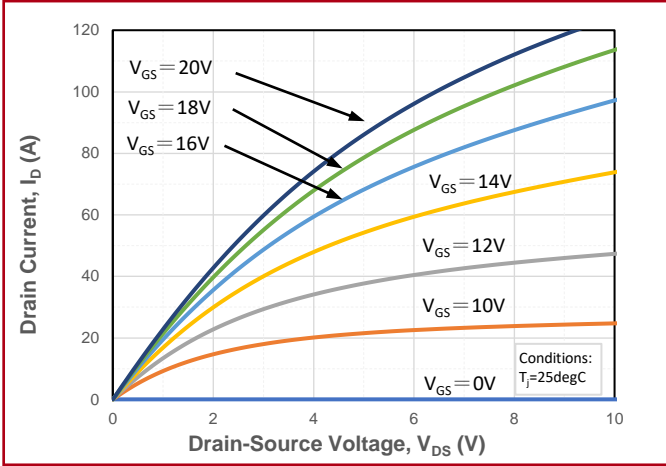


Fig.1 Forward Output Characteristics at $T_j=25^{\circ}\text{C}$

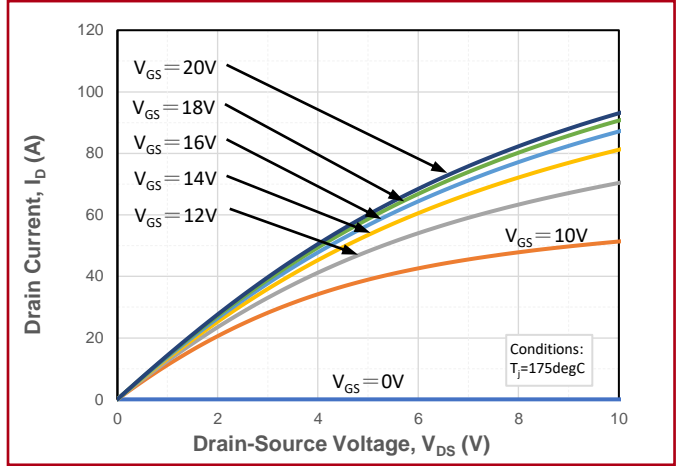


Fig.2 Forward Output Characteristics at $T_j=175^{\circ}\text{C}$

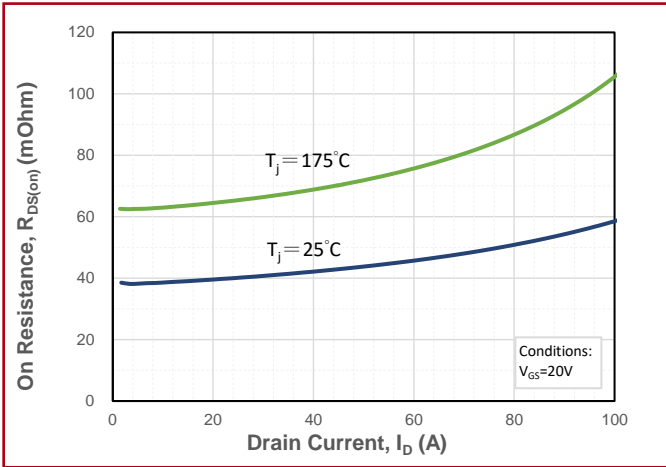


Fig.3 On-Resistance vs. Drain Current for Various T_j

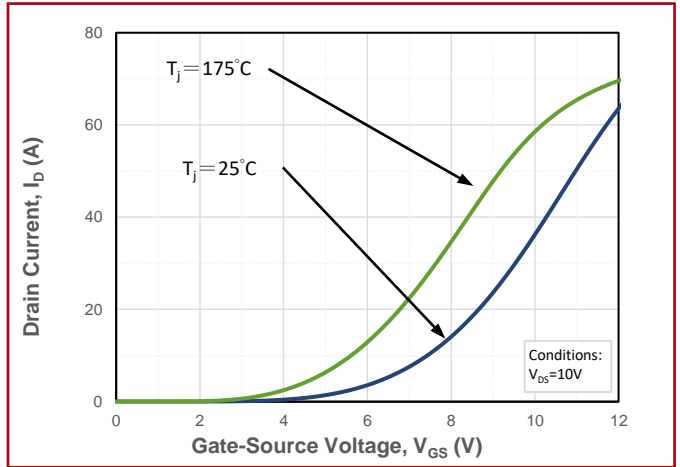


Fig.4 Transfer Characteristics for Various T_j

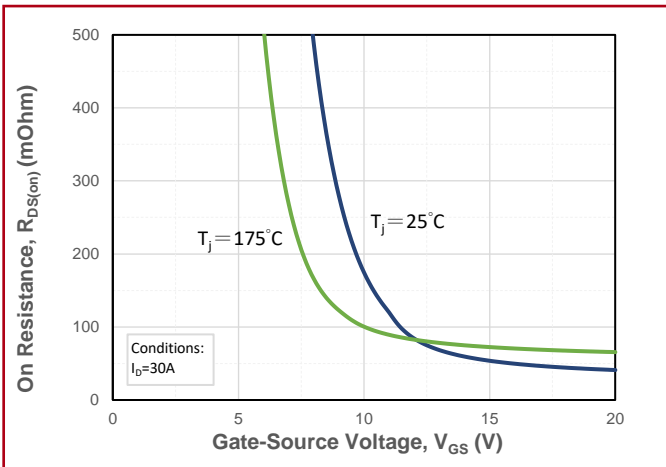


Fig.5 On-Resistance vs. Gate Voltage for Various T_j

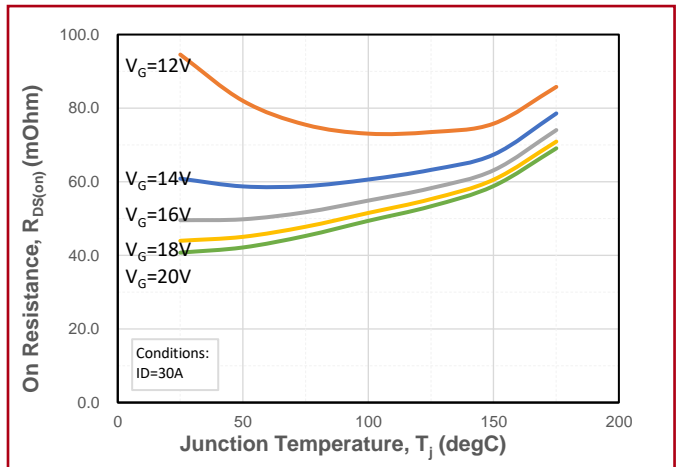


Fig.6 On-Resistance vs. Temperature for Various Gate Voltage

Typical Device Performance

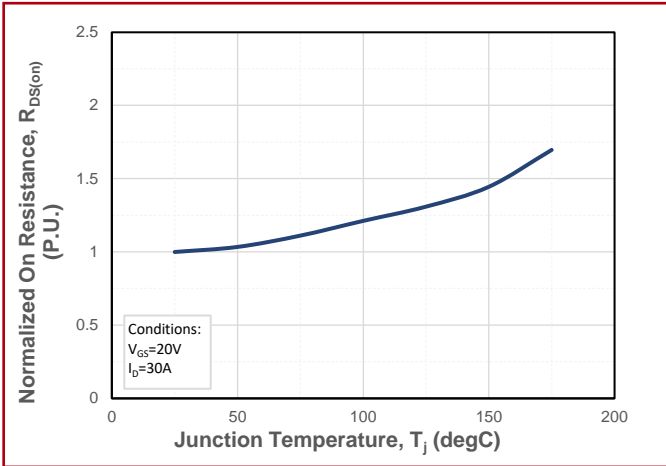


Fig.7 Normalized On-Resistance vs. Temperature

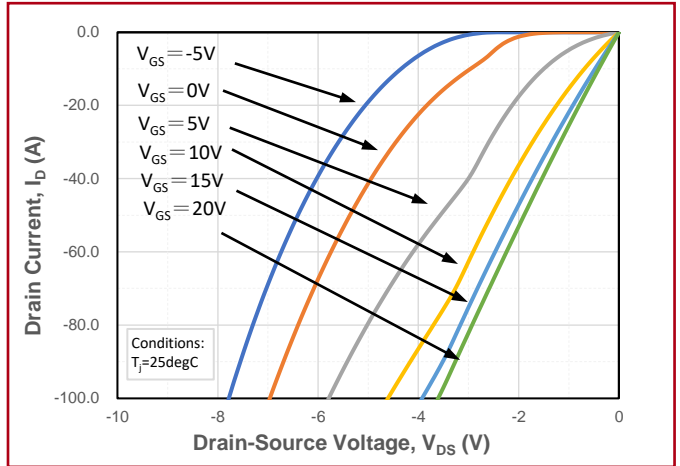


Fig.8 Reverse Output Characteristics at $T_j = 25^\circ C$

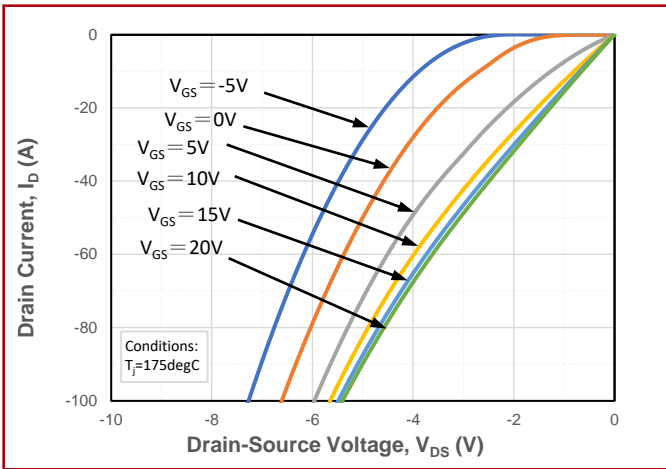


Fig.9 Reverse Output Characteristics at $T_j = 175^\circ C$

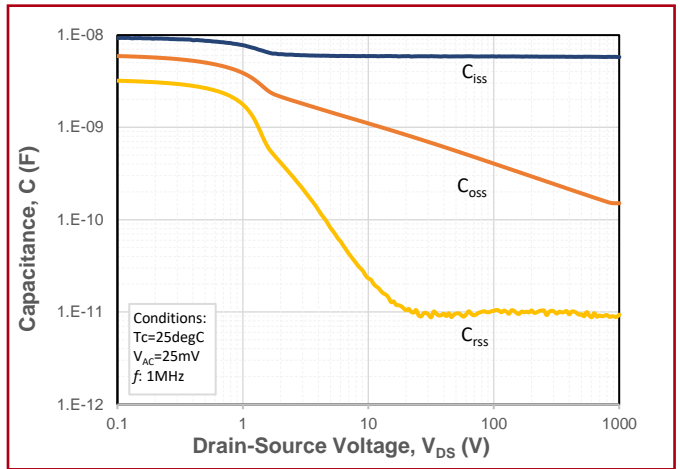


Fig.10 Capacitances vs. Drain to Source Voltage

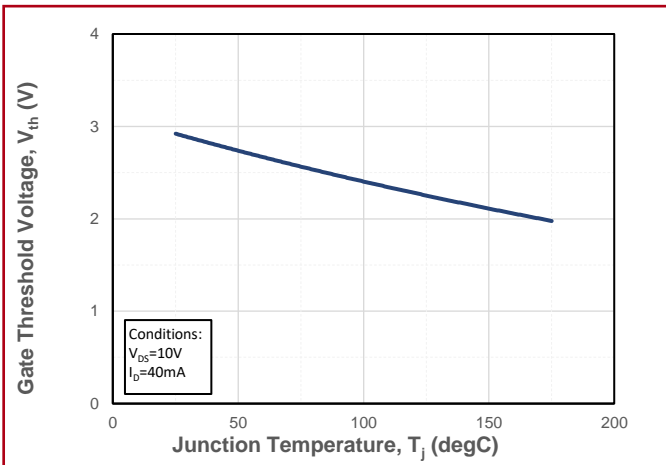


Fig.11 Threshold Voltage vs. Temperature

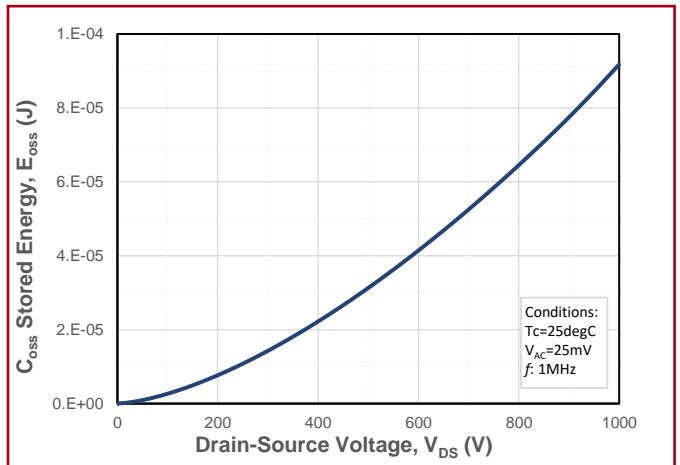


Fig.12 Output Capacitor Stored Energy

Typical Device Performance

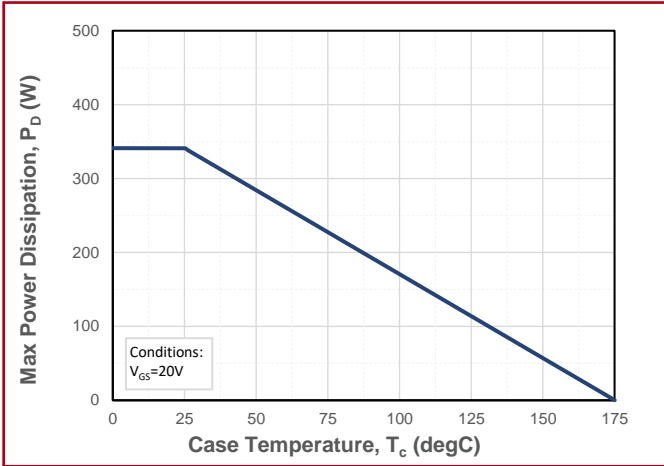


Fig.13 Maximum Power Dissipation Derating vs. Case Temperature

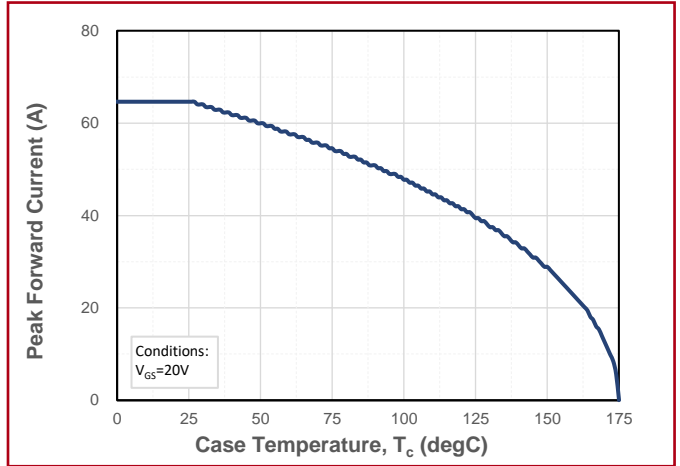


Fig.14 Drain Current Derating vs. Case Temperature

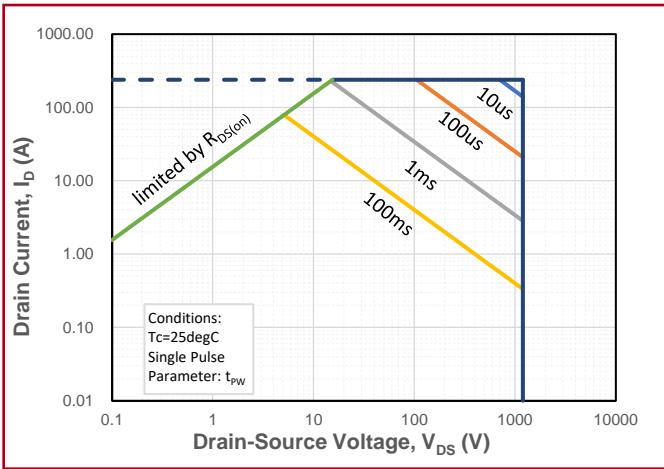


Fig.15 Safe Operating Area

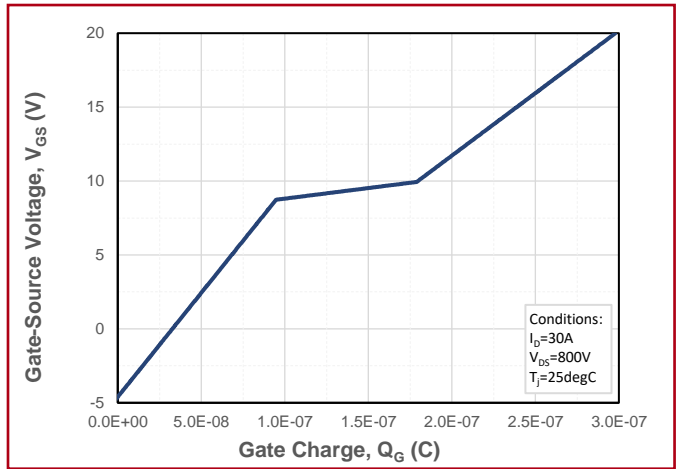


Fig.16 Gate Charge Characteristics

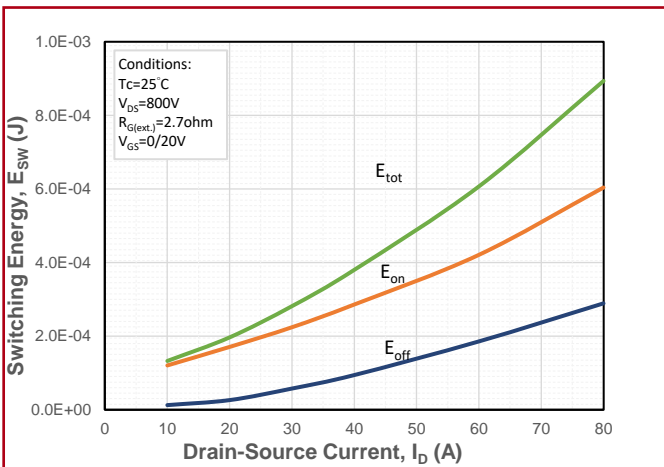


Fig.17 Clamped Inductive Switching Energy vs. Drain Current

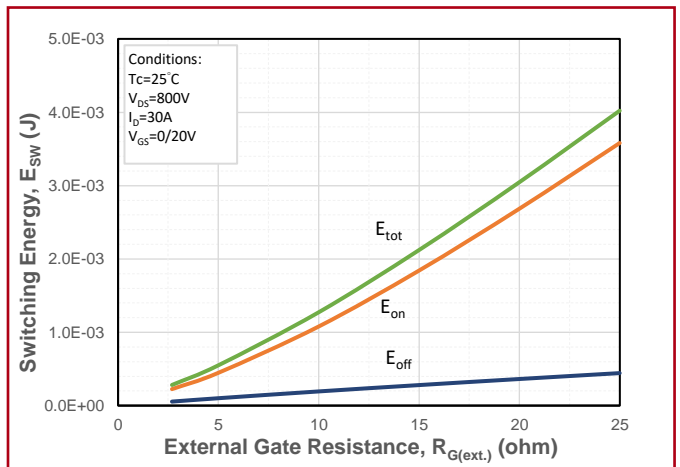


Fig.18 Clamped Inductive Switching Energy vs. External Gate Resistor ($R_{G(ext.)}$)

Typical Device Performance

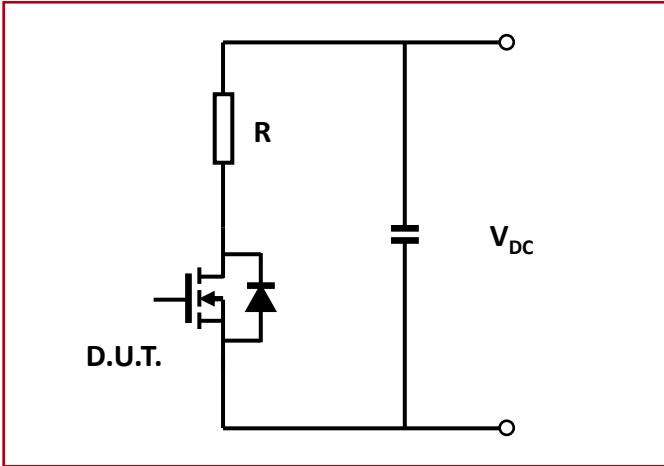


Fig.19 Schematic of Resistive Switching

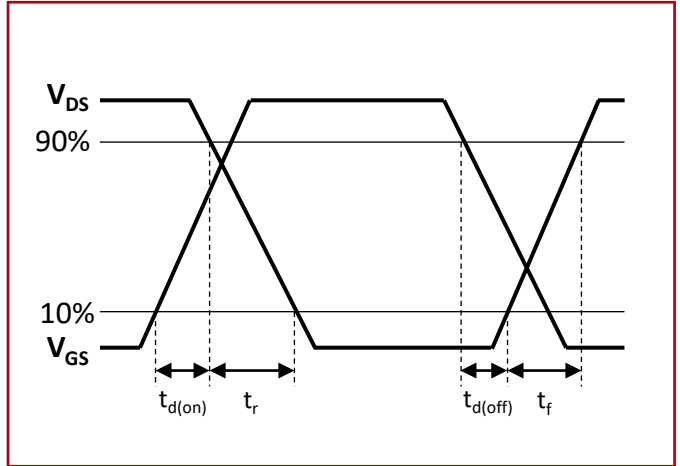


Fig.20 Switching Times Definition

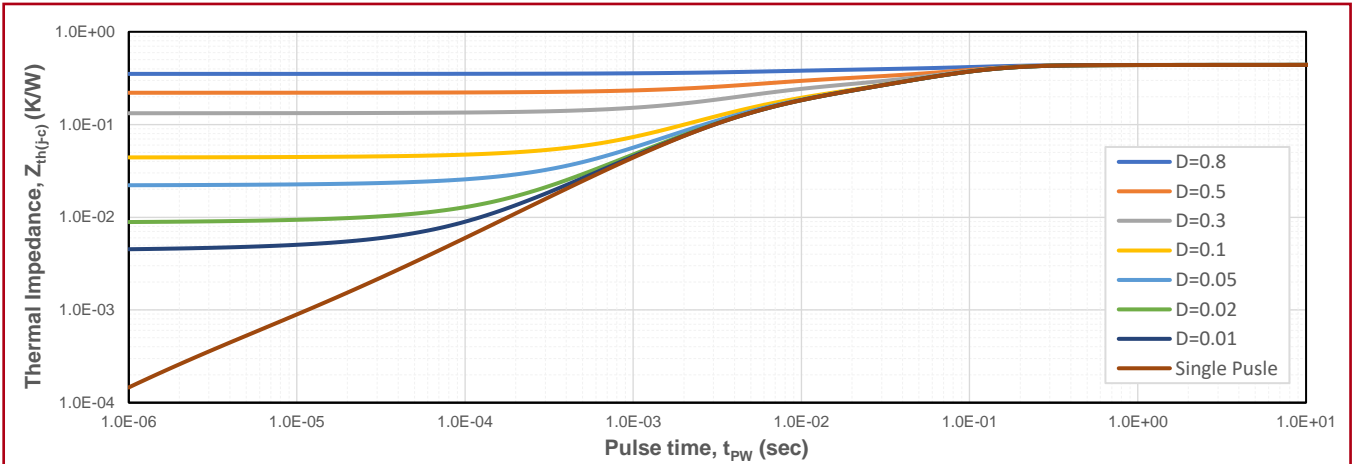


Fig.21 Transient Junction to Case Thermal Impedance

Naming Rule

H2 M 120 Q 040

Generation

H2 = 2nd Gen Discrete

Device Type

M = MOSFET J = JMOS

S = JBS diode

Breakdown Voltage

065 = 650V 170 = 1700V

120 = 1200V 330 = 3300V

Package

Q = TO-247-4L F = TO-247-3L

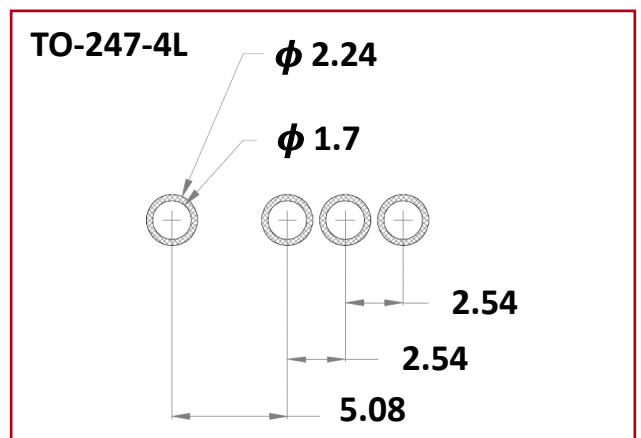
B = TO-220-3L T = TO-263-2L

Typical On-Resistance

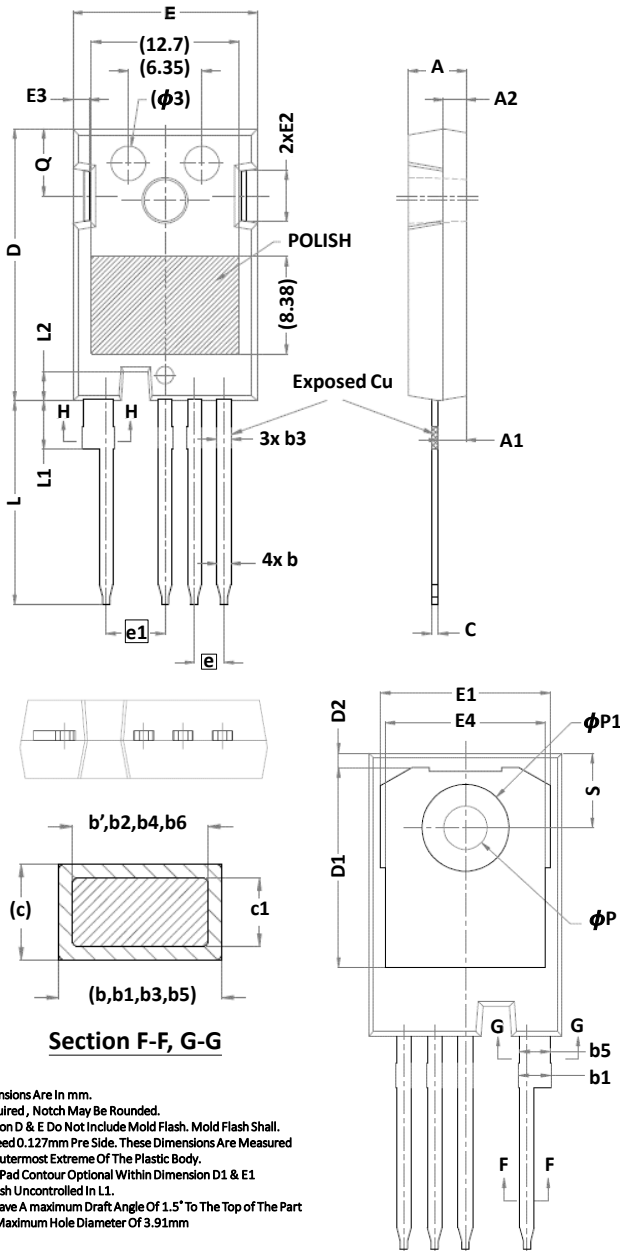
030 = 30mΩ 040 = 40mΩ 060 = 60mΩ

120 = 120mΩ 240 = 240mΩ

Recommended Solder Pad Layout



Package Dimensions



Symbol	mm		
	Min.	Typ.	Max.
A	4.83	5.02	5.21
A1	2.29	2.41	2.54
A2	1.91	2.00	2.16
b'	1.07	1.20	1.28
b	1.07	1.20	1.33
b1	2.39	2.67	2.94
b2	2.39	2.67	2.84
b3	1.07	1.30	1.60
b4	1.07	1.30	1.50
b5	2.39	2.53	2.69
b6	2.39	2.53	2.64
c	0.55	0.60	0.68
c1	0.55	0.60	0.65
D	23.30	23.45	23.60
D1	16.25	16.55	17.65
D2	0.95	1.19	1.25
E	15.75	15.94	16.13
E1	13.10	14.02	14.15
E2	3.68	4.40	5.10
E3	1.00	1.45	1.90
E4	12.38	13.26	13.43
e	2.54 BSC		
e1	5.08 BSC		
L	17.31	17.57	17.82
L1	3.97	4.19	4.37
L2	2.35	2.50	2.65
ϕP	3.51	3.61	3.65
$\phi P1$	7.19 REF.		
Q	5.49	5.79	6.00
S	6.04	6.17	6.30

Notes

- The information provided herein is subject to change without notice.
- For other information that does not show on this datasheet, please contact us for inquiry.